

## **MS/RF PCM/PROCESS CHECKLIST SUB-WORKING GROUP MINUTES**

**Date:** June 24, 2009  
**Location:** Teleconference  
**Time:** 10:00am (Pacific)  
**Participants:**

Chelsea Boone – GSA  
David Schwan – RF Micro Devices (RFMD)  
Ehrenfried Seebacher – austriamicrosystems AG  
Jay Seaton – Evolutionary Operations Consulting  
Hugues Lafontaine – SiGe Semiconductor  
Steffen Richter – X-FAB

### **Meeting Purpose:**

- To gather feedback on how the Sub-Working Group should go about developing a checklist that will help in communicating basic process parameters and criteria for mixed-signal and RF processes.

### **End Result/Conclusions:**

- For next month's meeting, David will combine austriamicrosystem's and X-FAB's parameters (what they measure) into one list for the group to review. We need to decide which parameters are necessary to measure for each device. This will then be incorporated into the PCM section which will be added to the existing Process Checklist.
- We will then need to discuss how the parameters are measured and what constitutes a pass/fail (does it vary by test?).

**Next Meeting:** July 22, 2009, 10:00am (Pacific)